

Supporting Information

Core-shell CuO@NiCoMn-LDH supported by copper foam for high-performance supercapacitors

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Characterization

Samples were characterized by scanning electron microscopy (SEM, Zeiss Supra 55) and the surface chemical compositions were identified on a Thermo Escalab 250Xi X-ray photoelectron spectroscopy (XPS) device. X-ray diffraction (XRD) patterns were recorded on a D/Max-RB X-ray diffractometer. Raman spectroscopy (Horiba LabRAM confocal Raman spectrometer with an excitation laser of 632.8 nm). Transmission electron microscopy (TEM) measurements were characterized on an FEI Tecnai F30 electron microscope at an accelerating voltage of 300 kV.

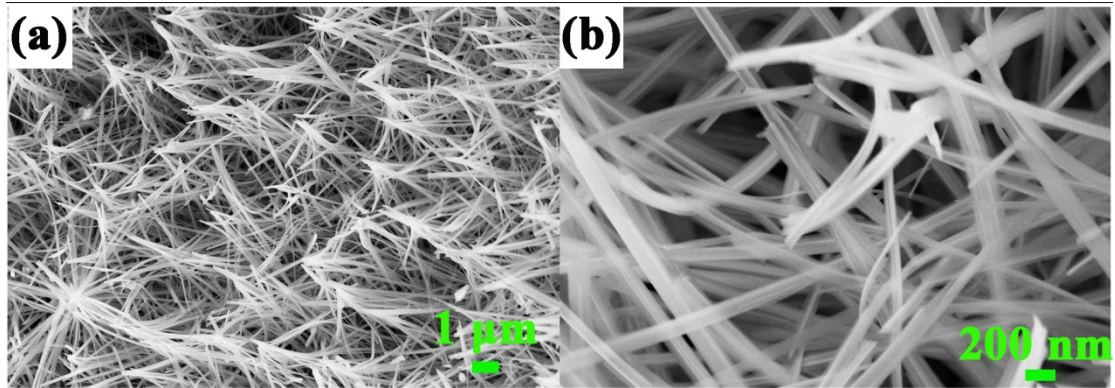


Fig. S1. SEM image of $\text{Cu}(\text{OH})_2$ nanowires grown on CF.

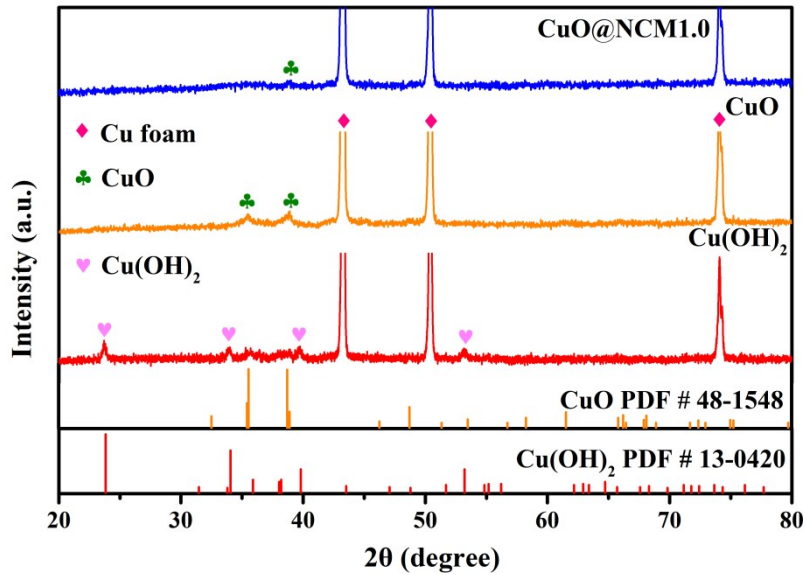


Fig. S2 XRD patterns of the as-prepared $\text{Cu}(\text{OH})_2$, CuO and CuO@NCM1.0 .

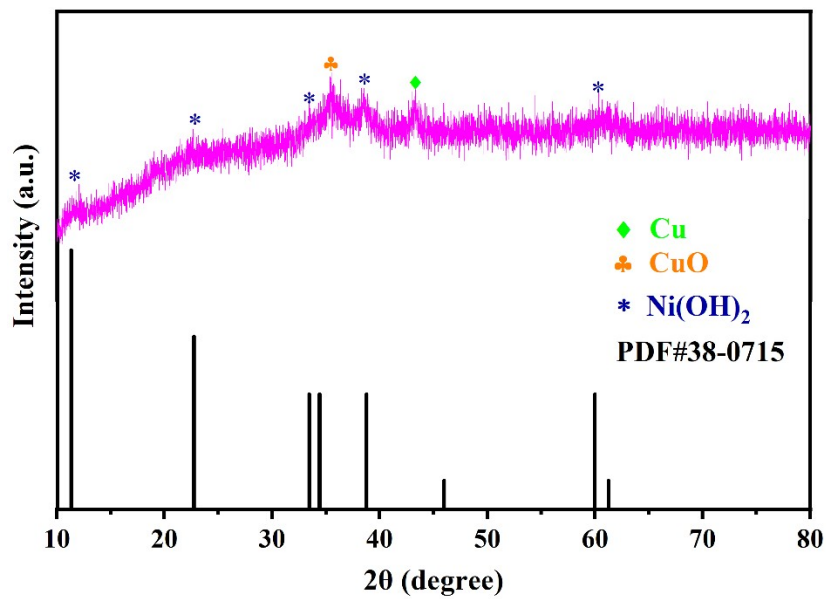


Fig. S3. The XRD pattern of CuO@NCM1.0 peeled off from the CF.

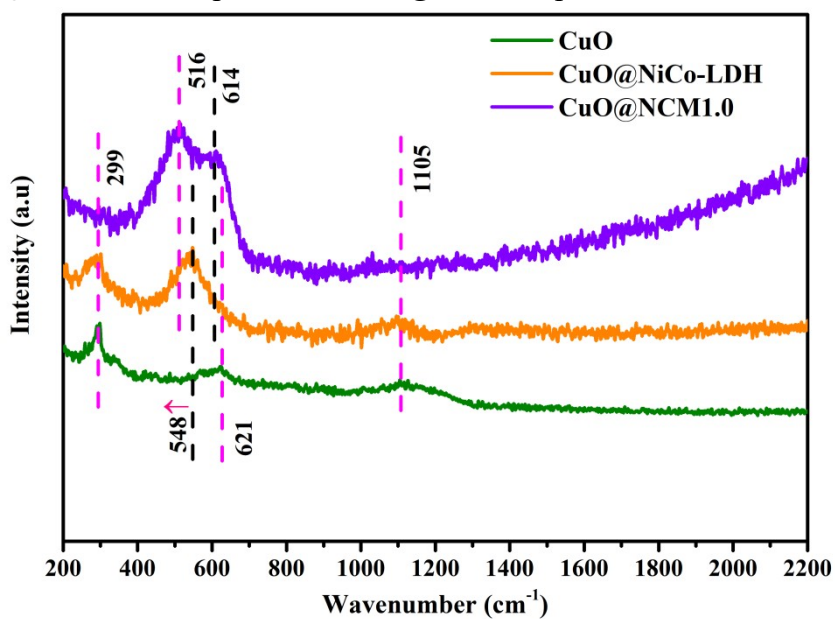


Fig. S4 Raman spectra of the CuO, CuO@NiCo-LDH, CuO@NCM1.0.

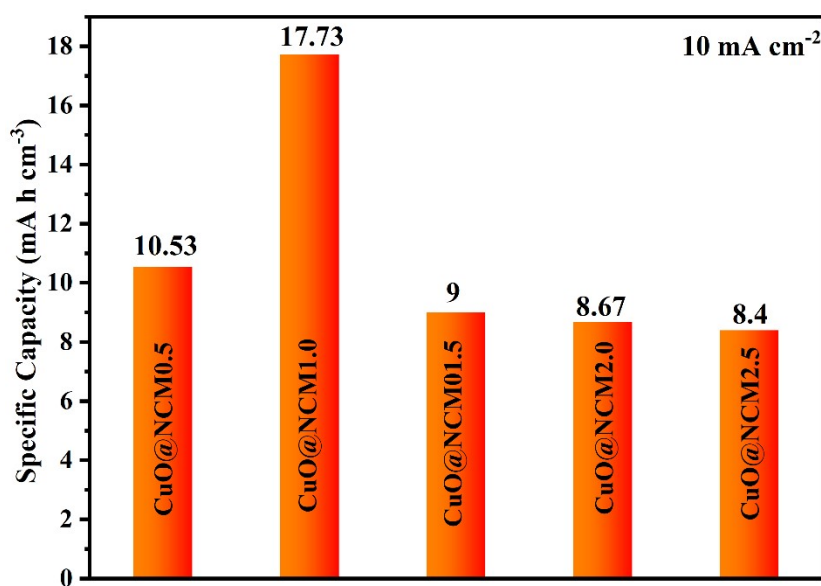


Fig. S5. Volumetric capacity comparison of CuO@NiCoMn-LDH series samples.

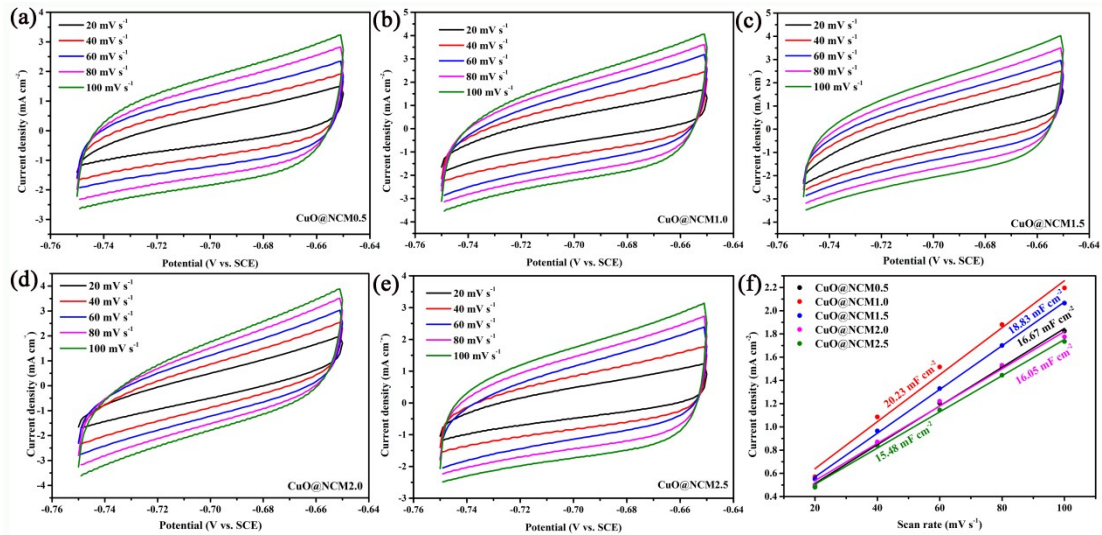


Fig. S6 (a) Cyclic voltammogram curves of CuO@NCM0.5, (b) CuO@NCM1.0, (c) CuO@NCM1.5, (d) CuO@NCM2.0, (e) CuO@NCM2.5 measured in the range of -0.75 ~ -0.65 V at different scan rates: 20, 40, 60, 80, and 100 $\text{mV}\cdot\text{s}^{-1}$. (f) Electrochemical double-layer capacitance measurements of samples.

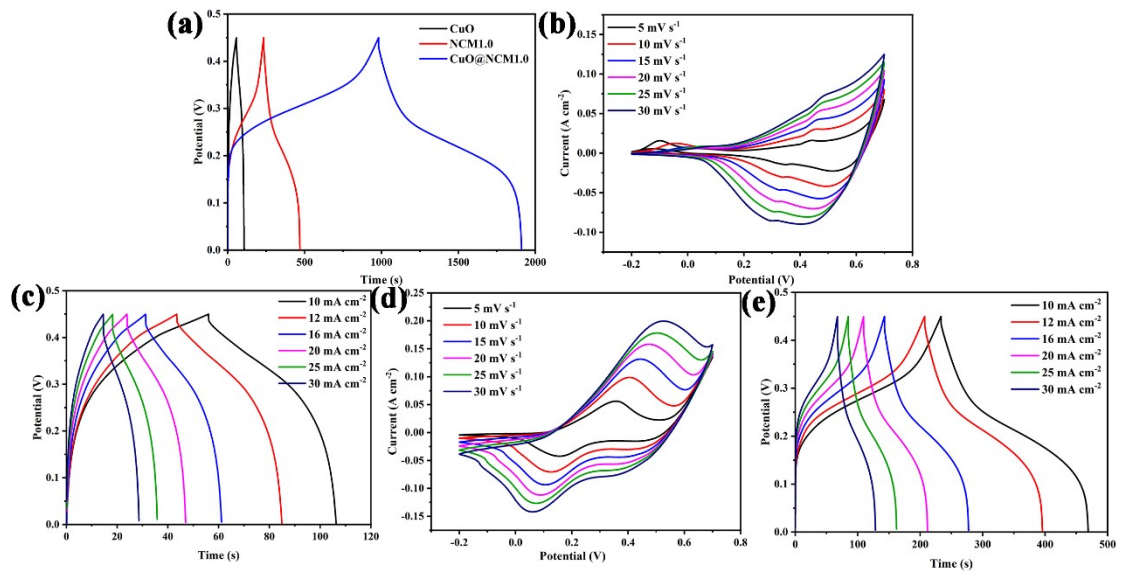


Fig. S7. (a) GCD curves of CuO, NCM1.0 and CuO@NCM1.0 at $10 \text{ mA}\cdot\text{cm}^{-2}$. (b-c) CV and GCD curves under different scan rates and different current densities of CuO. (c-d) CV and GCD curves of NCM1.0.

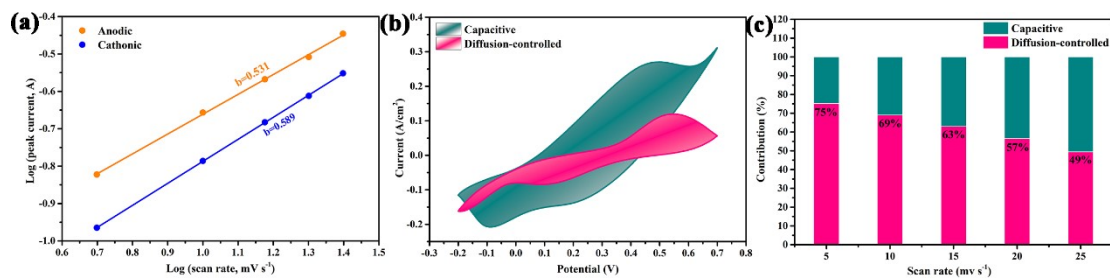


Fig. S8 (a) Logarithmic relationship between anode peak and cathode peak current and scan rate.
 (b) Capacitive contribution and diffusion contribution of CuO@NiCoMn1.0 electrode at 15 mV·s⁻¹.
 (c) The contribution rate of diffusion control and capacitance control of CuO@NiCoMn1.0 at different scan rates.

Table S1. Performance comparison between CuO@NiCoMn1.0 LDH and other electrode materials.

Electrode material	Electrolyte	Specific capacitance	Cycling stability	Ref.
NiCo@Ni ₂ Co1/CFC	1M KOH	9.67 F·cm ⁻² (at 5 mA·cm ⁻²)	75% (2000 cycles at 5 mA·cm ⁻²)	[1]
Cu ₃ N@CoFe-LDH	2M KOH	3.08 F·cm ⁻² (at 1 mA·cm ⁻²)	93.9% (10000 cycles at 20 mA·cm ⁻²)	[2]
Zn-Ni-Co TOH	1M KOH	2.14 F·cm ⁻² (at 3 mA·cm ⁻²)	108.6% (10000 cycles at 100 mV·s ⁻¹)	[3]
4M-P@NiCo LDH	6M KOH	7 F·cm ⁻² (at 50 mA·cm ⁻²)	77.17% (5000 cycles at 10 A·g ⁻¹)	[4]
H-NiCo LDH@ACC	1M KOH	3.06 F·cm ⁻² (at 1 mA·cm ⁻²)	70% (10000 cycles at 80 mA·cm ⁻²)	[5]
CCCH@NiCo-LDH	3M KOH	1.97 F·cm ⁻² (at 7.96 mA·cm ⁻²)	90.8% (30000 cycles at 7.96 mA·cm ⁻²)	[6]
NWAs@Au-CuO/Cu fibers				
CC/NiCoP@NiCo-LDH	6M KOH	4.683 F·cm ⁻² (at 1 mA·cm ⁻²)	81.1% (5000 cycles at 20 mA·cm ⁻²)	[7]
CuO@NCM1.0	2M KOH	20.7 F·cm ⁻² (at 10 mA·cm ⁻²)	94.82% (3000 cycles at 30 mA·cm ⁻²)	This work

Table S2. Comparative areal capacitances, areal energy and power densities of recently reported ASCs with our ASCs.

ASC device	Ca (F cm ⁻²)	Ea (mWh cm ⁻²)	Pa (mW cm ⁻²)	Ref
CoO@MnO ₂ //AC	0.91	0.37	1.7	[8]
CMO@NS-8//AC	1.16	0.412	4	[9]
NiCo ₂ O ₄ @CC//ACC	0.75	0.24	0.75	[10]
Co/CoO//AC	1.62	0.51	2.03	[11]
CuCo ₂ O ₄ /CuO@NiCo ₂ S ₄ //AC	2.3	0.824	8	[12]
Co ₃ S ₄ @Ni ₃ S ₄ //PC	0.513	0.19	1.72	[13]
CoAl-LDHs//rGO	1.77	0.71	17.05	[14]
Cu ₂ S@NiCo-LDH DSNA//NPC	4.2	1.67	4.25	[15]
CuO@NCM1.0//Fe ₃ O ₄ @C/CuO	7.52	2.67	4.79	This work

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